L	Hits	Search Text	DB	Time stamp
Number				
1	1702	(single adj package) and test	USPAT;	2004/09/17
		'	EPO; JPO;	15:34
			DERWENT;	
			USOCR	
2	151	1 '	USPAT;	2004/09/17
		mutual\$2	EPO; JPO;	15:31
		<u></u>	DERWENT;	
			USOCR	
3	127	((USPAT;	2004/09/17
		mutual\$2) and process\$2	EPO; JPO;	15:31
			DERWENT;	
			USOCR	2004/00/07
4	51	1	USPAT;	2004/09/17
		mutual\$2) and process\$2) and	EPO; JPO;	15:32
		manufacturing	DERWENT;	
_	1		USOCR	0004/00/17
5	104	(single adj package) and (test adj mode)	USPAT;	2004/09/17
			EPO; JPO;	15:34
			DERWENT;	
_	40	(/	USOCR USPAT;	2004/09/17
6	40	((single adj package) and (test adj mode)) and (control adj circuit)	EPO; JPO;	15:46
		mode) and (control ad) circuit)	DERWENT;	15:46
			USOCR	
7	36	 (burn adj in adj test) and chip	USPAT;	2004/09/17
 	1	(buin ad) in ad) test, and chip	EPO; JPO;	15:49
1			DERWENT;	13.45
			USOCR	
8	228	(test adj control adj circuit) and chip	USPAT;	2004/09/17
Ĭ	1	(total any compact any carrows of and only	EPO; JPO;	15:50
	1		DERWENT;	
	1		USOCR	
9	38	((test adj control adj circuit) and chip)	USPAT;	2004/09/17
ĺ		and inhibit\$3	EPO; JPO;	15:50
			DERWENT;	
			USOCR	